

**Search Notes**

Application/Control No.

10/661,638

Examiner

Lois Zheng

Applicant(s)/Patent under  
Reexamination

HIRAIWA ET AL.

Art Unit

1742

**SEARCHED**

Class	Subclass	Date	Examiner
204	276	7/15/2006	LLZ
204	242	7/15/2006	LLZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship Search	7/15/2006	LLZ
Updated EAST Search	7/15/2006	LLZ